

Search Notes

Application/Control No.

10/626,707

Examiner

Paul D. Kim

Applicant(s)/Patent under
Reexamination

KISHI ET AL.

Art Unit

3729

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3**SEARCHED**

Class	Subclass	Date	Examiner
29	603.07 603.13- 603.16 603.18	2/24/2006	PK
360	324.1		
	324.11		
	324.12		
216	41,62,66		
	67		
257	295	2/27/2006	PK
324	252		
365	158 171 173		
428	212 332 336		
	692 694 900		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Reviewed Parent Application 10/097,571 (US PAT. 6.605.836)	2/24/2006	PK
Text Search EAST/NPL (IEEE)	2/27/2006	PK